Title (en)

METHOD FOR TESTING AN ELECTRIC CIRCUIT

Title (de)

VERFAHREN ZUM PRÜFEN EINER ELEKTRISCHEN SCHALTUNG

Title (fr)

PROCEDE DE CONTROLE DE CIRCUIT ELECTRIQUE

Publication

EP 1665104 A2 20060607 (DE)

Application

EP 04762738 A 20040831

Priority

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Abstract (en)

[origin: WO2005026994A2] The invention relates to a method for testing an electric circuit, wherein exhaustive electric circuit modulation is not required yet circuit errors can be recognized in a reliable manner. According to the invention, a marking signal is produced, indicating a predefined circuit state which might occur in specific components of an electric circuit, wherein a transformed network list is formed from an original network list describing the circuit, whereby all electric components at least of one predefined component group, with regard to a respective connection pair, are treated as short-circuited, all network nodes connected by one or several components which are to be treated as short-circuited are respectively combined to form an equivalence category, wherein respectively all states of the associated network nodes are assigned to each equivalence category, it is possible to determine whether and in which components the predefined circuit state can occur by taking into account the equivalence categories. A signal which marks the identified components in the original network list is produced as the marking signal.

IPC 1-7

G06F 17/50

IPC 8 full level

G06F 17/50 (2006.01)

CPC (source: EP US)

G06F 30/327 (2020.01 - EP US); **G06F 30/33** (2020.01 - EP US); **G06F 30/3308** (2020.01 - US)

Citation (search report)

See references of WO 2005026994A2

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